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WHITE PAPER

Measuring and Correcting MicroLED Display Uniformity

Methods to Measure Subpixel Luminance and Chromaticity for Correction (Demura) and Quality Control



A Konica Minolta Company

Measuring and Correcting MicroLED Display Uniformity

MicroLEDs unlock next-level display performance, but inherent variability between LEDs can result in visual quality issues that impede production volumes needed for commercialization. Imaging systems have been proven for microLED test and correction, providing measurement data for display calibration at speed. Read a whitepaper to learn measurement system specifications, test methods, and image processing techniques for the most accurate pixel uniformity correction in microLED production.

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